

Joint DEPFET/PXD and SVD Workshop in Göttingen

Tuesday, 25 September 2012

PXD Testsystems and results (09:00 - 10:30)

time	[id] title	presenter
09:00	[46] Gated Mode & System Simulation	KOFFMANE, Christian
09:20	[47] Hybrid 5.0 DHP/DCD	LÜTTIKE, Florian
09:35	[48] Latest Results on Irradiation	KLEINOHL, Tobias
09:50	[49] Pixel Error Simulation in BASF2	KODYS, Peter
10:10	[50] A Study of Delta Electrons in Silicon Detectors Using DEPFET Active Pixel Sensors	WILK, Fabian